

FCC SDoC Test Report

For

Applicant Name:

Address:

EUT Name: Brand Name:

Model Number:

SHENZHEN YUNJI INTELLIGENT TECHNOLOGY CO.,LTD A2 2F BUILDNG ENET NEW INDUSTRIAL PARK, DAFU INDUSTRIAL ZONE, GUANLAN, LONGHUA SHENZHEN, 518XXX China Smart Phone OUKITEL C57 C57 S,C57 Pro,C57 Plus,C57 Ultra

Issued By

Company Name:

Series model number

BTF Testing Lab (Shenzhen) Co., Ltd.

Address:

F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China

Report Number: Test Standards: BTF240729E00201 47 CFR Part 15, Subpart B

Test Conclusion: FCC ID: Test Date: Date of Issue: Pass 2ANMU-C57 2024-07-30 to 2024-08-22 2024-08-22

Ace Xie / Project Engineer

Test By:

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Xing.Chen/ Tester

Ale the

Ryan.CJ / EMC 2024-08-22

2024-08-22

Prepared By:

Date:

Approved By:

Date:

Note: All the test results in this report only related to the testing samples. Which can be duplicated completely for the legal use with approval of applicant; it shall not be reproduced except in full without the written approval of BTF Testing Lab (Shenzhen) Co., Ltd., All the objections should be raised within thirty days from the date of issue. To validate the report, you can contact us.

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Revision History			
Version	Issue Date	Revisions Content	18 47
R_V0	2024-08-22	Original	

Note: Once the revision has been made, then previous versions reports are invalid.



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1 Introduction

1.1 Identification of Testing Laboratory

Company Name: BTF Testing Lab (Shenzhen) Co., Ltd.			
Address: F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tan Community, Songgang Street, Bao'an District, Shenzhen, China			
Phone Number:	+86-0755-23146130		
Fax Number:	+86-0755-23146130		

1.2 Identification of the Responsible Testing Location

BTF Testing Lab (Shenzhen) Co., Ltd.
F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou
Community, Songgang Street, Bao'an District, Shenzhen, China
+86-0755-23146130
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518915
CN1330

1.3 Announcement

(1) The test report reference to the report template version v0.

(2) The test report is invalid if not marked with the signatures of the persons responsible for preparing, reviewing and approving the test report.

(3) The test report is invalid if there is any evidence and/or falsification.

(4) This document may not be altered or revised in any way unless done so by BTF and all revisions are duly noted in the revisions section.

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(6) The laboratory is only responsible for the data released by the laboratory, except for the part provided by the applicant.



2 **Product Information**

2.1 Application Information

Company Name:		SHENZHEN YUNJI INTELLIGENT TECHNOLOGY CO., LTD	
	Address:	A2 2F BUILDNG ENET NEW INDUSTRIAL PARK, DAFU INDUSTRIAL ZONE, GUANLAN, LONGHUA SHENZHEN, 518XXX China	

2.2 Manufacturer Information

Company Name:	SHENZHEN YUNJI INTELLIGENT TECHNOLOGY CO.,LTD
Address:	A2 2F BUILDNG ENET NEW INDUSTRIAL PARK, DAFU INDUSTRIAL ZONE, GUANLAN, LONGHUA SHENZHEN, 518XXX China

2.3 Factory Information

Company Name: SHENZHEN YUNJI INTELLIGENT TECHNOLOGY CO.,LTD	
Address:	A2 2F BUILDNG ENET NEW INDUSTRIAL PARK, DAFU INDUSTRIAL ZONE, GUANLAN, LONGHUA SHENZHEN, 518XXX China

2.4 General Description of Equipment under Test (EUT)

EUT Name:	Smart Phone
Test Model Number:	C57
Series model name	C57 S,C57 Pro,C57 Plus,C57 Ultra
Description of model name differentiation	Only the model name is different, the others are the same.

2.5 Technical Information

Power Supply:	DC 5V from adaptor or DC 4.4V from battery
Power Adaptor:	Model:ZFX021 Input:100-240V, 50/60Hz 0.2A Output:DC5.0V 1000mA



3 Summary of Test Results

3.1 Test Standards

The tests were performed according to following standards: **47 CFR Part 15, Subpart B:** Unintentional Radiators

3.2 Uncertainty of Test

Item	Measurement Uncertainty
Conducted Emission (150 kHz-30 MHz)	±2.64dB
Radiated Emissions (30M - 1GHz)	±4.12dB
Radiated Emissions (above 1GHz)	1-6GHz: ±3.94dB 6-18GHz: ±4.16dB

The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

3.3 Summary of Test Result

Item	Standard	Requirement	Result
Conducted emissions on AC mains	47 CFR Part 15, Subpart B	15.107, Class B	Pass
Radiated emissions (Below 1GHz)	47 CFR Part 15, Subpart B	15.109, Class B	Pass
Radiated emissions (Above 1GHz)	47 CFR Part 15, Subpart B	15.109, Class B	Pass



4 Test Configuration

4.1 Test Equipment List

Conducted emissions on AC mains					
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
Pulse Limiter	SCHWARZBECK	VTSD 9561-F	00953	/	/
Coaxial Switcher	SCHWARZBECK	CX210	CX210	/	/
V-LISN	SCHWARZBECK	NSLK 8127	01073	2023-11-16	2024-11-15
LISN	AFJ	LS16/110VAC	16010020076	2023-11-16	2024-11-15
EMI Receiver	ROHDE&SCHWA RZ	ESCI3	101422	2023-11-15	2024-11-14

Radiated emissions (I Radiated emissions (/					
Equipment	Manufacturer	Model No	Inventory No	Cal Date	Cal Due Date
Coaxial cable Multiflex 141	Schwarzbeck	N/SMA 0.5m	517386	/	/
Preamplifier	SCHWARZBECK	BBV9744	00246	/	/
RE Cable	REBES Talent	UF1-SMASMAM-1 0m	21101566	/	/
RE Cable	REBES Talent	UF2-NMNM-10m	21101570	1	1
RE Cable	REBES Talent	UF1-SMASMAM-1 m	21101568	1	/
RE Cable	REBES Talent	UF2-NMNM-1m	21101576	1	1
RE Cable	REBES Talent	UF2-NMNM-2.5m	21101573	1	/
POSITIONAL CONTROLLER	SKET	PCI-GPIB	1	/	/
Horn Antenna	SCHWARZBECK	BBHA9170	01157	2023-11-13	2024-11-12
EMI TEST RECEIVER	ROHDE&SCHWA RZ	ESCI7	101032	2023-11-16	2024-11-15
SIGNAL ANALYZER	ROHDE&SCHWA RZ	FSQ40	100010	2023-11-16	2024-11-15
POSITIONAL CONTROLLER	SKET	PCI-GPIB	1	/	/
Broadband Preamplilifier	SCHWARZBECK	BBV9718D	00008	2023-11-15	2024-11-14
Horn Antenna	SCHWARZBECK	BBHA9120D	2597	2023-11-15	2024-11-14
EZ_EMC	Frad	FA-03A2 RE+	/	1	/
POSITIONAL CONTROLLER	SKET	PCI-GPIB	1	1	1
Log periodic antenna	SCHWARZBECK	VULB 9168	01328	2023-11-13	2024-11-12



4.2 Test Auxiliary Equipment

The EUT was tested as an independent device.

4.3	Fest Modes	
No.	Test Modes	Description
TM1	Charging+working Mode	



5 Emission Test Results (EMI)

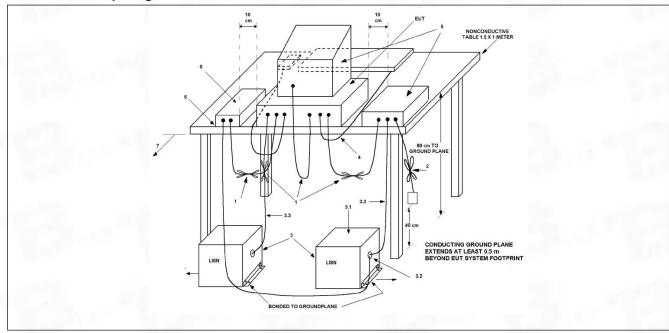
5.1 Conducted emissions on AC mains

Test Requirement:	15.107, Class B						
Test Method:	ANSI C63.4-2014						
	Frequency of emission (MHz)	Conducted limit (dBµV)				
		Quasi-peak	Average				
Test Limit:	0.15-0.5	66 to 56*	56 to 46*				
	0.5-5	56	46				
	5-30	60	50				
	*Decreases with the logarithm of	*Decreases with the logarithm of the frequency.					
Procedure:	An initial pre-scan was performed we measurement were performed at the were detected. Remark: Level= Read Level+ Cable	ne frequencies with ma					

5.1.1 E.U.T. Operation:

Operating Environment:		
Temperature:	24.7 °C	
Humidity:	52 %	
Atmospheric Pressure:	1010 mbar	

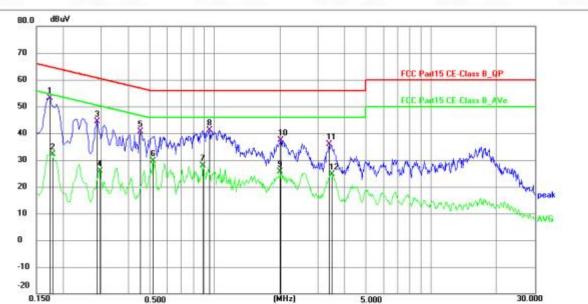
5.1.2 Test Setup Diagram:





5.1.3 Test Data:

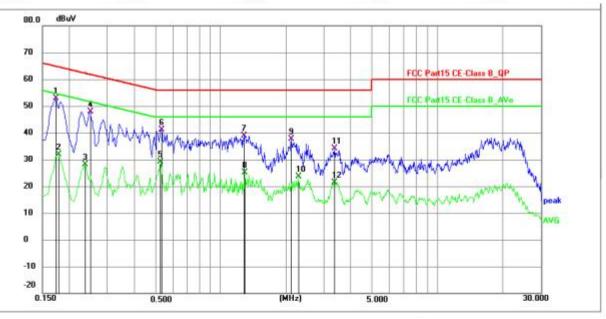
TM1 / Line: Line



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB)	Level (dBuV)	Limit (dBuV)	Margin (dB)	Detector	P/F	Remark
1 *	0.1724	42.52	10.49	53.01	64.84	-11.83	QP	Р	
2	0.1770	21.52	10.51	32.03	54.63	-22.60	AVG	P	
3	0.2850	33.94	10.56	44.50	60.67	-16.17	QP	P	
4	0.2940	15.36	10.56	25.92	50.41	-24.49	AVG	P	
5	0.4515	30.05	10.57	40.62	56.85	-16.23	QP	Ρ	
6	0.5190	18.99	10.59	29.58	46.00	-16.42	AVG	P	
7	0.8834	17.26	10.68	27.94	46.00	-18.06	AVG	P	
8	0.9465	30.40	10.67	41.07	56.00	-14.93	QP	P	
9	2.0040	15.05	10.68	25.73	46.00	-20.27	AVG	P	
10	2.0220	26.65	10.68	37.33	56.00	-18.67	QP	Р	
11	3.3720	25.18	10.64	35.82	56.00	-20.18	QP	P	
12	3.4620	14.09	10.63	24.72	46.00	-21.28	AVG	P	



TM1 / Line: Neutral



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB)	Level (dBuV)	Limit (dBuV)	Margin (dB)	Detector	P/F	Remark
1 *	0.1724	42.28	10.49	52.77	64.84	-12.07	QP	P	
2	0.1770	21.42	10.51	31.93	54.63	-22.70	AVG	P	
3	0.2354	17.54	10.56	28.10	52.26	-24.16	AVG	P	
4	0.2490	37.39	10.56	47.95	61.79	-13.84	QP	P	
5	0.5234	18.57	10.59	29.16	46.00	-16.84	AVG	P	
6	0.5324	30.61	10.60	41.21	56.00	-14.79	QP	P	
7	1.2884	28.24	10.66	38.90	56.00	-17.10	QP	P	
8	1.2930	14.35	10.66	25.01	46.00	-20.99	AVG	P	
9	2.1120	26.83	10.68	37.51	56.00	-18.49	QP	Р	
10	2.2964	13.00	10.67	23.67	46.00	-22.33	AVG	P	
11	3.3540	23.42	10.64	34.06	56.00	-21.94	QP	P	
12	3.3540	10.85	10.64	21.49	46.00	-24.51	AVG	P	



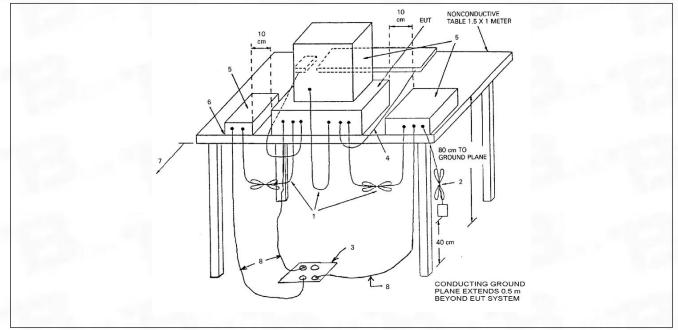
5.2 Radiated emissions (Below 1GHz)

Test Requirement:	15.109, Class B							
Test Method:	ANSI C63.4-2014							
	Except for Class A digital devices, the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:							
	Frequency of emission (MHz)	Field str @3m	ength	Field str	ength @10m			
Test Limit:		(uV/m)	(dBuV/ m)	(uV/m)	(dBuV/m)			
	30 – 88	100	40	30	29.5			
	88 – 216	150	43.5	45	33.1			
	216 – 960	200	46	60	35.6			
	Above 960	500	54	150	43.5			
Procedure:	An initial pre-scan was perforn peak detection mode. Quasi-p peak sweep graph. The EUT v orthogonal polarities. Remark: Level= Read Level+	eak measure vas measure	ements wer d by BiCon	e conducte iLog anter	ed based on the nna with 2			

5.2.1 E.U.T. Operation:

Operating Environment:		
Temperature:	24.6 °C	
Humidity:	52 %	
Atmospheric Pressure:	1010 mbar	

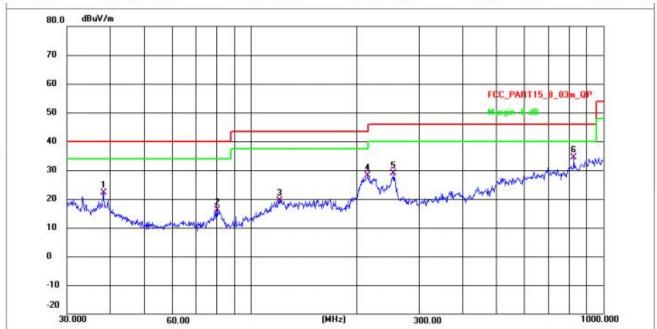
5.2.2 Test Setup Diagram:





5.2.3 Test Data:

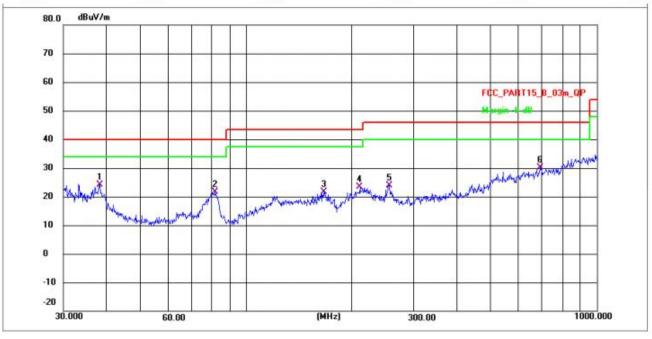




No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	38.1451	31.87	-9.64	22.23	40.00	-17.77	QP	Р
2	80.2211	25.44	-9.27	16.17	40.00	-23.83	QP	P
3	120.9109	41.73	-22.27	19.46	43.50	-24.04	QP	P
4	215.2678	49.42	-21.38	28.04	43.50	-15.46	QP	P
5	254.2821	49.88	-21.02	28.86	46.00	-17.14	QP	P
6 *	827.4934	51.82	-17.41	34.41	46.00	-11.59	QP	P



TM1 / Polarization: Vertical



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1 *	38.2120	33.83	-9.64	24.19	40.00	-15.81	QP	P
2	81.2117	30.83	-9.27	21.56	40.00	-18.44	QP	P
3	166.0680	43.61	-21.86	21.75	43.50	-21.75	QP	P
4	211.1559	44.69	-21.42	23.27	43.50	-20.23	QP	P
5	255.6231	44.94	-21.00	23.94	46.00	-22.06	QP	Р
6	690.7745	47.79	-17.68	30.11	46.00	-15.89	QP	P



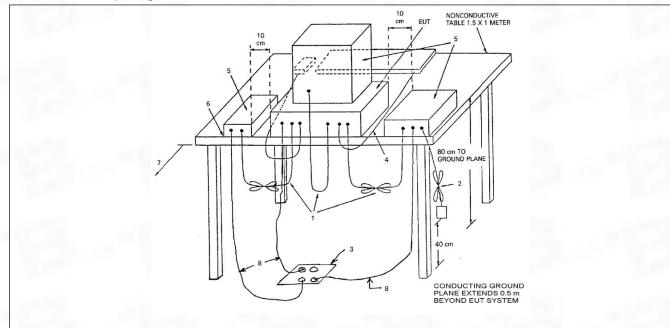
5.3 Radiated emissions (Above 1GHz)

Test Requirement:	15.109, Class B	CI DALLA					
Test Method:	ANSI C63.4-2014						
	Frequency of emission (MHz)	Field stren	gth @3m				
Test Limit:		Average (uV/m)					
	Above 1GHz	500	54	74			
Procedure:	An initial pre-scan was performed i peak detection mode. For below 10 conducted based on the peak swee antenna with 2 orthogonal polarities were conducted based on the peak antenna with 2 orthogonal polarities Remark: Level= Read Level+ Cabl	GHz test, Quas ep graph. The s. For above 10 s sweep graph. s.	si-peak measure EUT was measu GHz test, Averaç The EUT was n	ements were ired by BiConiLog ge measurements neasured by Horr			

5.3.1 E.U.T. Operation:

Operating Environment:	
Temperature:	24.7 °C
Humidity:	52 %
Atmospheric Pressure:	1010 mbar

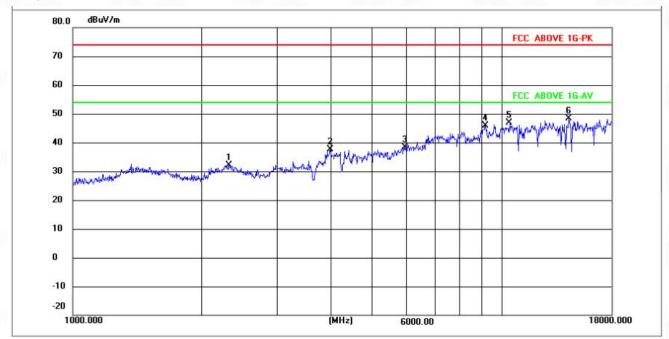
5.3.2 Test Setup Diagram:





5.3.3 Test Data:

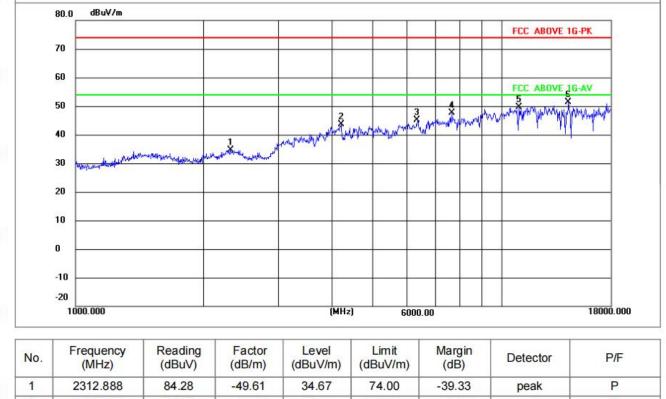
TM1 / Polarization: Horizontal



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB/m)	Level (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Detector	P/F
1	2312.888	81.78	-49.61	32.17	74.00	-41.83	peak	P
2	3990.474	87.11	-49.40	37.71	74.00	-36.29	peak	P
3	5965.308	86.65	-48.34	38.31	74.00	-35.69	peak	Р
4	9165.716	91.71	-45.73	45.98	74.00	-28.02	peak	P
5	10438.873	92.00	-45.16	46.84	74.00	-27.16	peak	Р
6 *	14329.515	92.16	-43.81	48.35	74.00	-25.65	peak	P



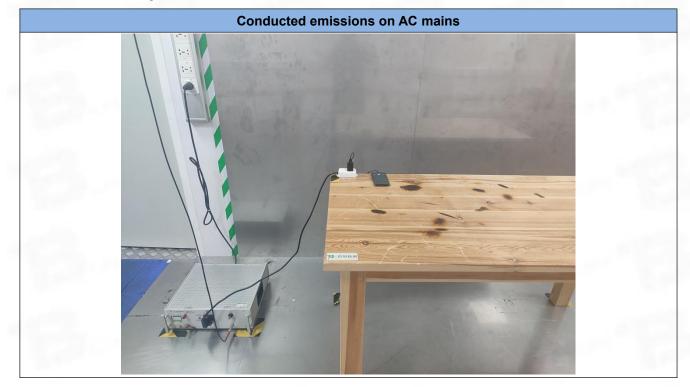
TM1 / Polarization: Vertical



	2312.000	04.20	-49.01	34.07	74.00	-39.33	peak	F
2	4193.872	92.80	-49.28	43.52	74.00	-30.48	peak	P
3	6351.441	93.15	-47.96	45.19	74.00	-28.81	peak	P
4	7648.677	94.02	-46.49	47.53	74.00	-26.47	peak	P
5	10980.469	94.34	-44.82	49.52	74.00	-24.48	peak	P
6 *	14329.515	95.16	-43.81	51.35	74.00	-22.65	peak	P



6 Test Setup Photos

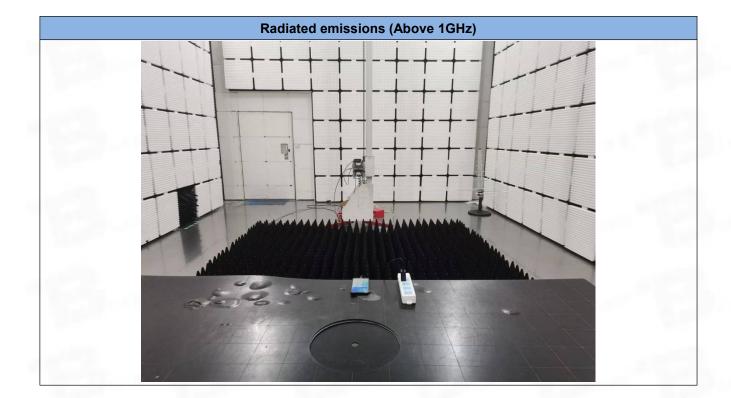


Radiated emissions (Below 1GHz)

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7 EUT Constructional Details (EUT Photos)

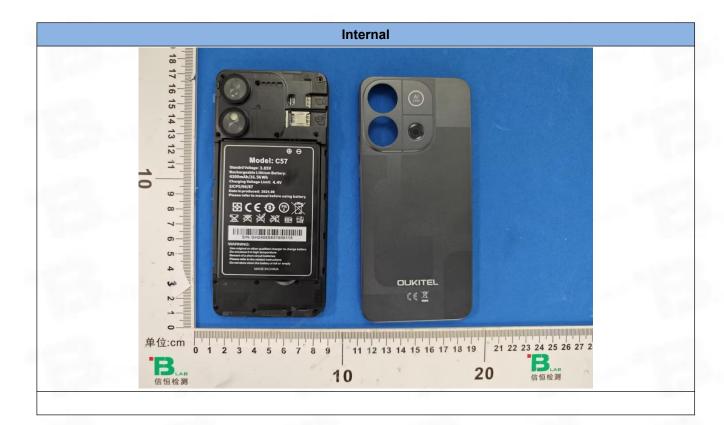


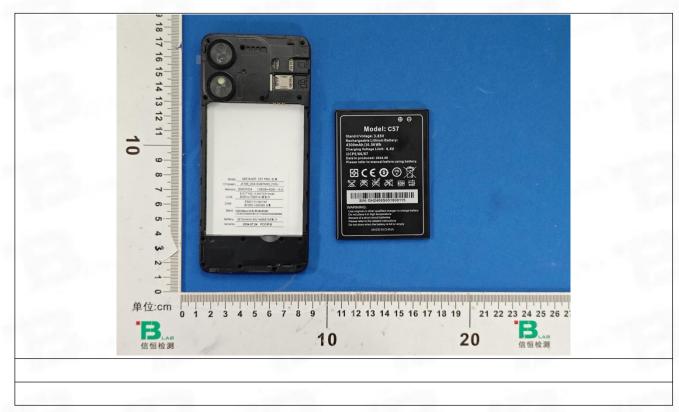
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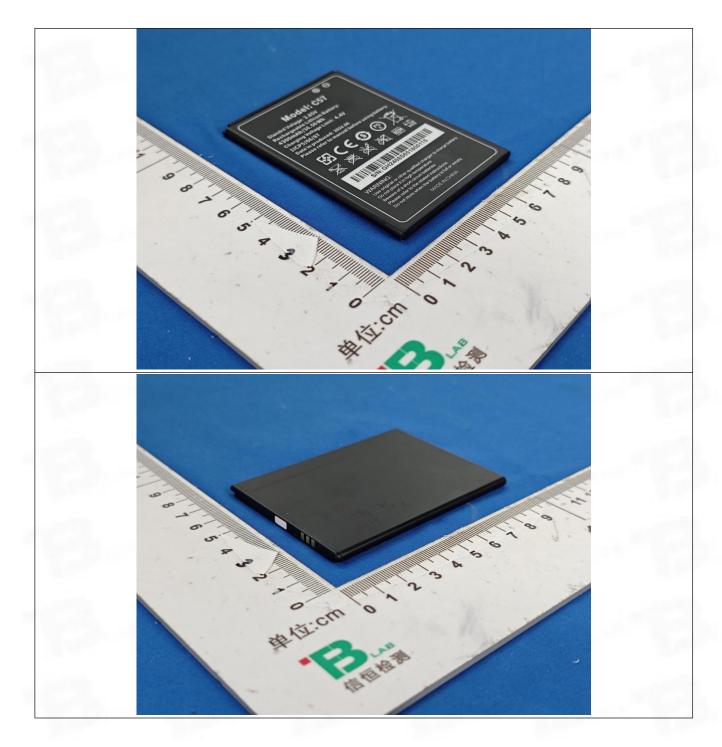






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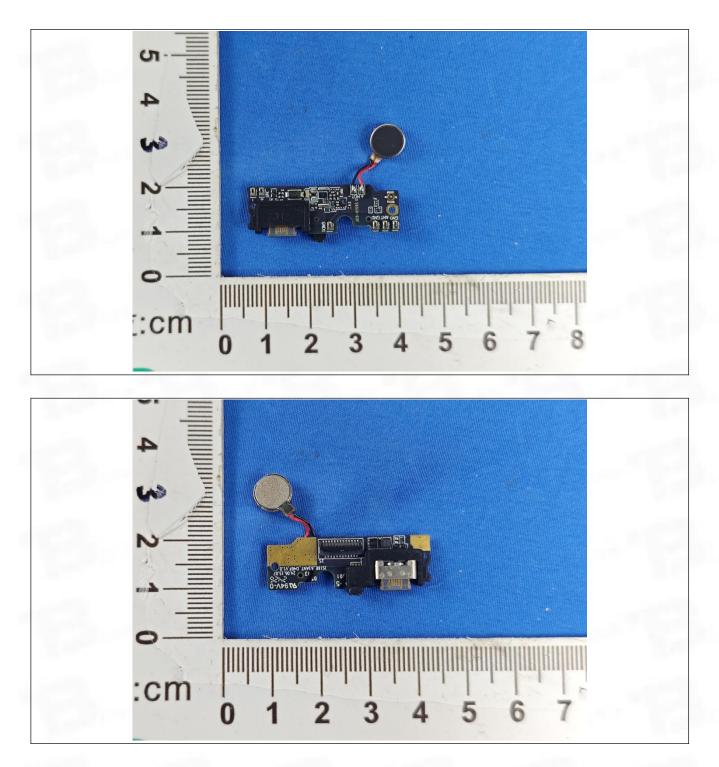






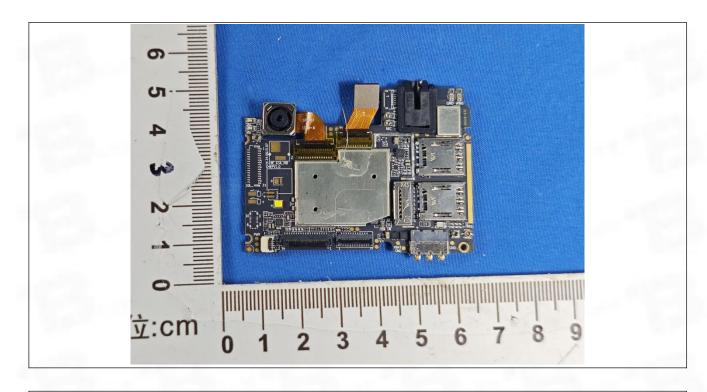
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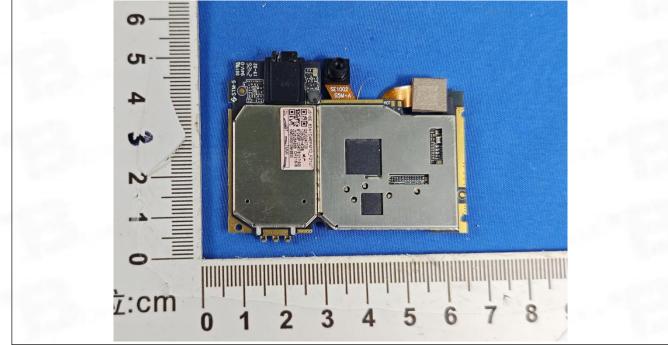




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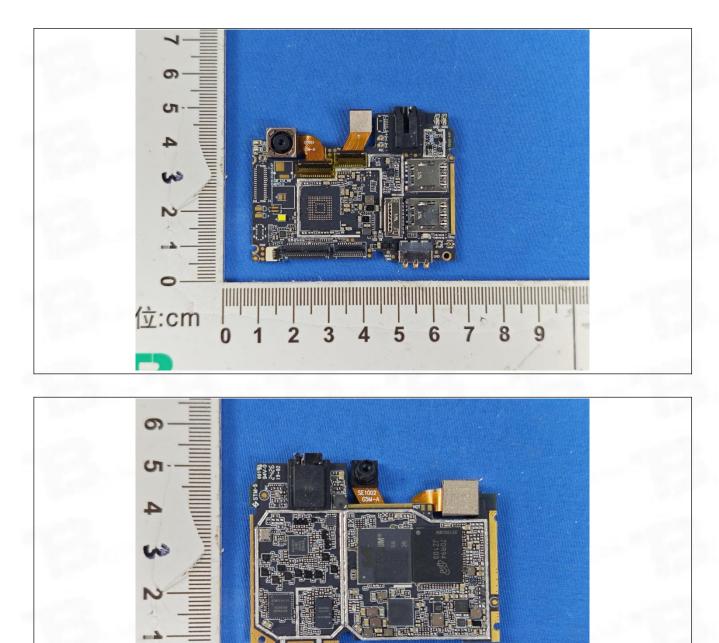




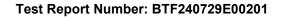


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Test Report Number: BTF240729E00201



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